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# 2-Mbit (128 K × 16) Static RAM

#### **Features**

- Temperature ranges
  □ Automotive-E: -40 °C to 125 °C
- High speed

  □ t<sub>AA</sub> = 10 ns
- Low active power □ 468 mW (max)
- 2.0 V data retention
- Automatic power down when deselected
- Independent control of upper and lower bits
- Easy memory expansion with Chip Enable (CE) and Output Enable (OE) features
- Available in Pb-free 48-ball grid array (BGA) package

## **Functional Description**

The CY7C1011CV33 Automotive is a high performance complementary metal oxide semiconductor (CMOS) static RAM organized as 131,072 words by 16 bits. This device has an automatic power down feature that significantly reduces power consumption when deselected.

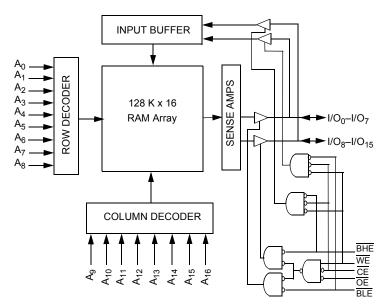
To write to the device, take  $\overline{\text{CE}}$  and Write Enable ( $\overline{\text{WE}}$ ) inputs LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O<sub>0</sub> through I/O<sub>7</sub>), is written into the location specified on the address pins (A<sub>0</sub> through A<sub>16</sub>). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O<sub>8</sub> through I/O<sub>15</sub>) is written into the location specified on the address pins (A<sub>0</sub> through A<sub>16</sub>).

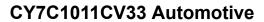
To read from the device, take  $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  LOW while forcing the Write Enable ( $\overline{\text{WE}}$ ) HIGH. If  $\overline{\text{BLE}}$  is LOW, then data from the memory location specified by the address pins appear on I/O<sub>0</sub> to I/O<sub>7</sub>. If Byte High Enable ( $\overline{\text{BHE}}$ ) is LOW, then data from memory appears on I/O<sub>8</sub> to I/O<sub>15</sub>. For more information, see the Truth Table on page 10 for a complete description of Read and Write modes.

The input and output pins (I/O $_0$  through I/O $_{15}$ ) are <u>placed</u> in a high impedance state when <u>the</u> device is des<u>elected</u> (CE HIGH), the outputs are <u>disabled</u> (OE HIGH), the BHE and <u>BLE</u> are <u>disabled</u> (BHE, BLE HIGH), or during a write operation (CE LOW and WE LOW).

For a complete list of related resources, click here.

## Logic Block Diagram







### Contents

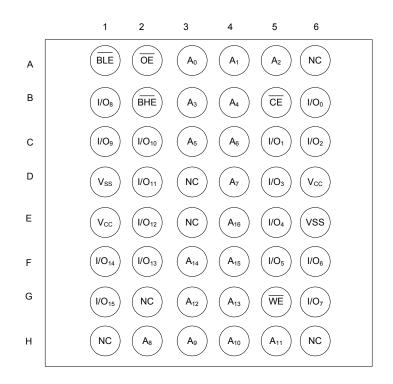
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# **Pin Configuration**

Figure 1. 48 ball BGA pinout [1]



## **Selection Guide**

Description			Unit
Maximum access time		10	ns
Maximum operating current	Automotive-E	130	mA
Maximum CMOS standby current	Automotive-E	15	mA

#### Note

<sup>1.</sup> NC pins are not connected on the die.



## **Maximum Ratings**

Exceeding maximum ratings may shorten the useful life of the device. These user guidelines are not tested. Storage temperature ......—65 °C to +150 °C Ambient temperature with power applied ......–55 °C to +125 °C Supply voltage on  $V_{CC}$  relative to GND  $^{[2]}.....-0.5$  V to +4.6 V

DC voltage applied to outputs in High Z state  $^{[2]}$  ......-0.5 V to V  $_{CC}\text{+}$  0.5 V

Operating Range	
Latch up current	> 200 mA
Static discharge voltage (MIL-STD-883, method 3015)	> 2001 V
Current into outputs (LOW)	20 mA

Range	Ambient Temperature (T <sub>A</sub> )	V <sub>CC</sub>
Automotive-E	–40 °C to +125 °C	$3.3~V\pm10\%$

DC input voltage  $^{[2]}$  ......-0.5 V to V<sub>CC</sub>+ 0.5 V

### **Electrical Characteristics**

Over the Operating Range

Doromotor	Description	Test Condition	_	-	Unit	
Parameter	Description	Test Conditions	rest Conditions			Oille
V <sub>OH</sub>	Output HIGH voltage	V <sub>CC</sub> = Min, I <sub>OH</sub> = -4.0 mA		2.4	-	V
V <sub>OL</sub>	Output LOW voltage	V <sub>CC</sub> = Min, I <sub>OL</sub> = 8.0 mA		_	0.4	V
V <sub>IH</sub>	Input HIGH voltage			2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW voltage <sup>[2]</sup>			-0.3	0.8	V
I <sub>IX</sub>	Input leakage current	$GND \le V_I \le V_{CC}$	Automotive-E	-20	+20	μΑ
I <sub>OZ</sub>	Output leakage current	$\begin{aligned} & \text{GND} \leq \text{V}_{\text{I}} \leq \text{V}_{\text{CC}}, \\ & \text{Output disabled} \end{aligned}$	Automotive-E	-20	+20	μΑ
Icc	V <sub>CC</sub> operating supply current	$V_{CC}$ = Max, $I_{OUT}$ = 0 mA, f = f <sub>MAX</sub> = 1/t <sub>RC</sub>	Automotive-E		130	mA
I <sub>SB1</sub>	Automatic CE power down current – TTL Inputs	$\begin{aligned} &\text{Max V}_{CC}, \ \overline{CE} \geq V_{IH}, \\ &V_{IN} \geq V_{IH} \text{ or } V_{IN} \leq V_{IL}, \ f = f_{MAX} \end{aligned}$	Automotive-E		45	mA
I <sub>SB2</sub>	Automatic CE power down current – CMOS inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \ge \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ &\text{V}_{\text{IN}} \ge \text{V}_{\text{CC}} - 0.3 \text{ V}, \text{ or} \\ &\text{V}_{\text{IN}} \le 0.3 \text{ V}, \text{ f} = 0 \end{aligned}$	Automotive-E		15	mA

#### Note

<sup>2.</sup>  $V_{IL}$  (min) = -2.0 V for pulse durations of less than 20 ns.



## Capacitance

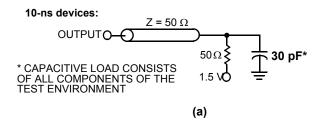
Parameter [3]	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 3.3 \text{V}$	8	pF
C <sub>OUT</sub>	Output capacitance		8	pF

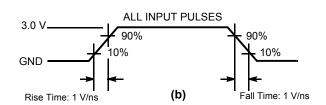
## **Thermal Resistance**

Parameter [3]	Description	Test Conditions	48-pin BGA	Unit
$\Theta_{JA}$	Thermal resistance (junction to ambient)	Still air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	38.15	°C/W
$\Theta_{\sf JC}$	Thermal resistance (junction to case)		9.15	°C/W

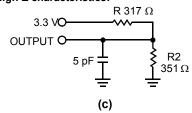
### **AC Test Loads and Waveforms**

Figure 2. AC Test Loads and Waveforms [4]





#### High-Z characteristics:



#### Notes

- 3. Tested initially and after any design or process changes that may affect these parameters.
- A AC characteristics (except High Z) for 10-ns parts are tested using the load conditions shown in Figure 2 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 2 (b).



## **Switching Characteristics**

Over the Operating Range

Parameter [5]	Description	-	10	Unit
Parameter [9]	Description		Max	Unit
Read Cycle		•	•	
t <sub>power</sub> <sup>[6]</sup>	V <sub>CC</sub> (typical) to the first access	1	-	μS
t <sub>RC</sub>	Read cycle time	10	-	ns
t <sub>AA</sub>	Address to data valid	-	10	ns
t <sub>OHA</sub>	Data hold from address change	3	-	ns
t <sub>ACE</sub>	CE LOW to data valid	-	10	ns
t <sub>DOE</sub>	OE LOW to data valid	-	6	ns
t <sub>LZOE</sub>	OE LOW to Low Z [7]	0	_	ns
t <sub>HZOE</sub>	OE HIGH to High Z [7, 8]	-	5	ns
t <sub>LZCE</sub>	CE LOW to Low Z [7]	3	_	ns
t <sub>HZCE</sub>	CE HIGH to High Z [7, 8]	-	5	ns
t <sub>PU</sub>	CE LOW to power up	0	-	ns
t <sub>PD</sub>	CE HIGH to power down	-	10	ns
t <sub>DBE</sub>	Byte enable to data valid	-	6	ns
t <sub>LZBE</sub>	Byte enable to Low Z	0	-	ns
t <sub>HZBE</sub>	Byte disable to High Z	-	6	ns
Write Cycle [9,	10]			
t <sub>WC</sub>	Write cycle time	10	-	ns
t <sub>SCE</sub>	CE LOW to write end	7	-	ns
t <sub>AW</sub>	Address setup to write end	7	-	ns
t <sub>HA</sub>	Address hold from write end	0	_	ns
t <sub>SA</sub>	Address setup to write start	0	-	ns
t <sub>PWE</sub>	WE pulse width	7	-	ns
t <sub>SD</sub>	Data setup to write end	5	_	ns
t <sub>HD</sub>	Data hold from write end	0	_	ns
t <sub>LZWE</sub>	WE HIGH to Low Z [7]	3	_	ns
t <sub>HZWE</sub>	WE LOW to High Z [7, 8]	-	5	ns
t <sub>BW</sub>	Byte enable to end of write	7	-	ns

- Notes

  Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V.

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  test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V.

  test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V.

  test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V.

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  test conditions assume signal transition to 4.2 V.

  test conditions assume signal transition to 4.2 V.

  test conditions assume signal transition to 4.2 V.

  test conditions assume sign



## **Switching Waveforms**

Figure 3. Read Cycle No. 1 (Address Transition Controlled) [11, 12]

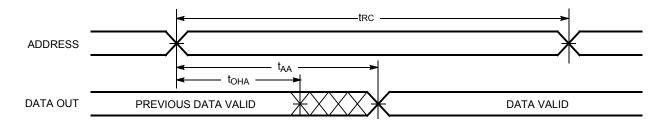
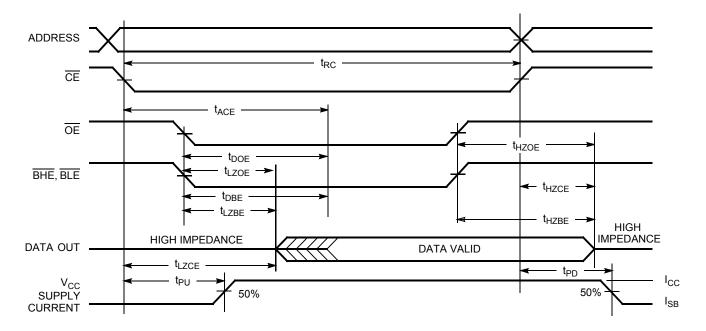


Figure 4. Read Cycle No. 2 (OE Controlled) [12, 13]



<sup>11. &</sup>lt;u>Devi</u>ce is continuously selected. <u>OE</u>, <u>CE</u>, <u>BHE</u>, and/or <u>BLE</u> = V<sub>IL</sub>. 12. <u>WE</u> is HIGH for read cycle.

<sup>13.</sup> Address valid prior to or coincident with  $\overline{\text{CE}}$  transition LOW.



## Switching Waveforms (continued)

Figure 5. Write Cycle No. 1 (CE Controlled) [14, 15]

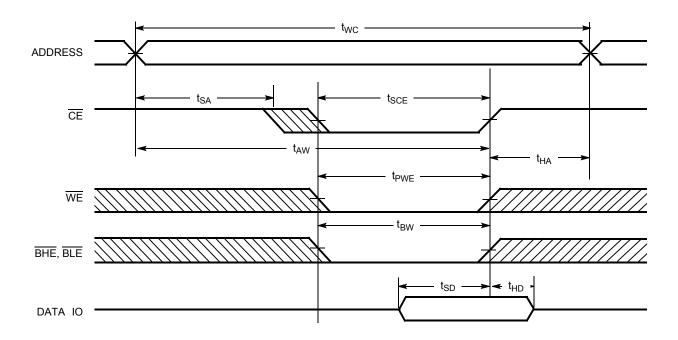
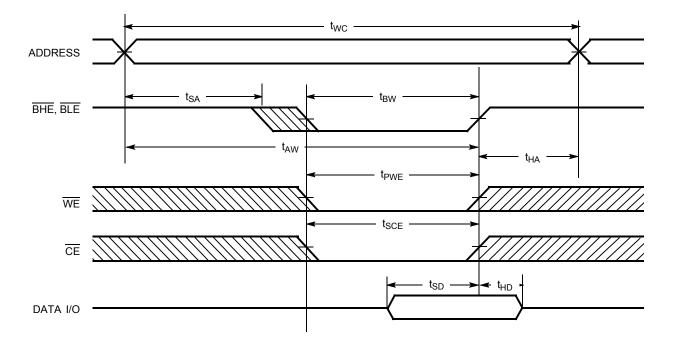


Figure 6. Write Cycle No. 2 (BLE or BHE Controlled)



Notes

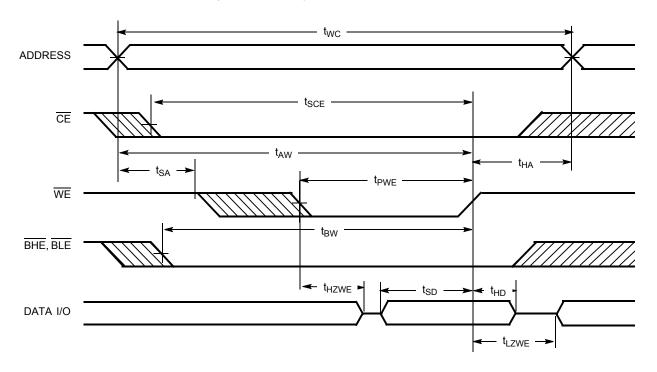
14. Data I/O is high impedance if  $\overline{OE}$ ,  $\overline{BHE}$ , and/or  $\overline{BLE}$  =  $V_{IH}$ .

15. If  $\overline{CE}$  goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.



## Switching Waveforms (continued)

Figure 7. Write Cycle No. 3 (WE Controlled, LOW)





# **Truth Table**

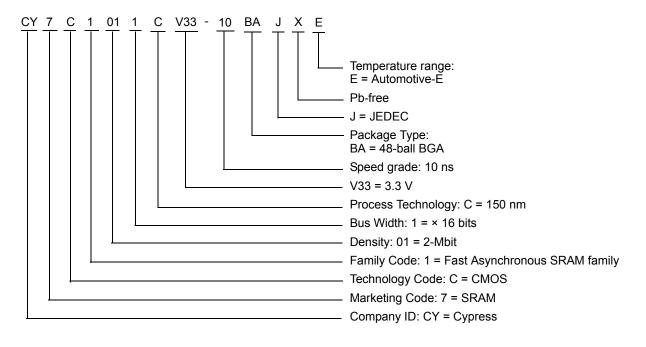
CE	OE	WE	BLE	BHE	I/O <sub>0</sub> -I/O <sub>7</sub>	I/O <sub>8</sub> -I/O <sub>15</sub>	Mode	Power
Н	Х	Х	X	Х	High Z	High Z	Power down	Standby (I <sub>SB</sub> )
L	L	Н	L	L	Data Out	Data Out	Read – all bits	Active (I <sub>CC</sub> )
L	L	Н	L	Н	Data Out	High Z	Read – lower bits only	Active (I <sub>CC</sub> )
L	L	Н	Н	L	High Z	Data Out	Read – upper bits only	Active (I <sub>CC</sub> )
L	Х	L	L	L	Data In	Data In	Write – all bits	Active (I <sub>CC</sub> )
L	Х	L	L	Н	Data In	High Z	Write – lower bits only	Active (I <sub>CC</sub> )
L	Х	L	Н	L	High Z	Data In	Write – upper bits only	Active (I <sub>CC</sub> )
L	Н	Н	Х	Х	High Z	High Z	Selected, outputs disabled	Active (I <sub>CC</sub> )



## **Ordering Information**

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1011CV33-10BAJXE	001-85259	48-ball BGA (Pb-free)	Automotive-E

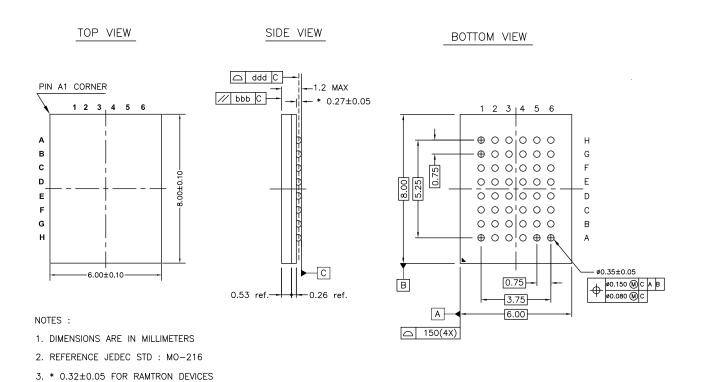
### **Ordering Code Definitions**





## **Package Diagrams**

Figure 8. 48-ball FBGA (6 × 8 × 1.2 mm) BA48M/BK48M (0.35 mm Ball Diameter) Package Outline, 001-85259



001-85259 \*A

Document Number: 001-86374 Rev. \*C



# Acronyms

Acronym	Description
BHE	Byte High Enable
BLE	Byte Low Enable
CMOS	Complementary Metal Oxide Semiconductor
CE	Chip Enable
I/O	Input/Output
ŌĒ	Output Enable
SRAM	Static Random Access Memory
TQFP	Thin Quad Flat Pack
TSOP	Thin Small Outline Package
TTL	Transistor-Transistor Logic
VFBGA	Very Fine-Pitch Ball Grid Array
WE	Write Enable

## **Document Conventions**

## **Units of Measure**

Symbol	Unit of Measure			
°C	degree Celsius			
MHz	megahertz			
μΑ	microampere			
μs	microsecond			
mA	milliampere			
mm	millimeter			
ms	millisecond			
mV	millivolt			
mW	milliwatt			
ns	nanosecond			
%	percent			
pF	picofarad			
V	volt			
W	watt			



# **Document History Page**

Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	3924592	TAVA	03/12/2013	New data sheet.
*A .	4055409	MEMJ	07/10/2013	Changed status from Preliminary to Final.
				Updated Package Diagrams: spec 001-85259 – Changed revision from ** to *A.
				Updated to new template.
*B	4075559	MEMJ	07/24/2013	Updated Ordering Information: No change in part numbers. Changed package diagram spec number from "51-85087" to "001-85259" in "Package Diagram" column.
*C	4729519	PSR	04/17/2015	Updated Functional Description: Added "For a complete list of related resources, click here." at the end. Updated to new template.



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